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# Synthetic Data for Defect Segmentation on Complex Metal Surfaces

Juraj Fulir, Lovro Bosnar, Hans Hagen, Petra Gospodnetić

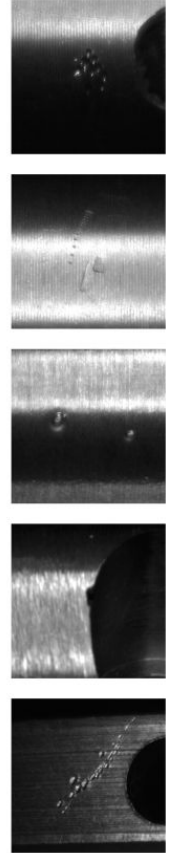
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CVPR 2023 - VISION Workshop



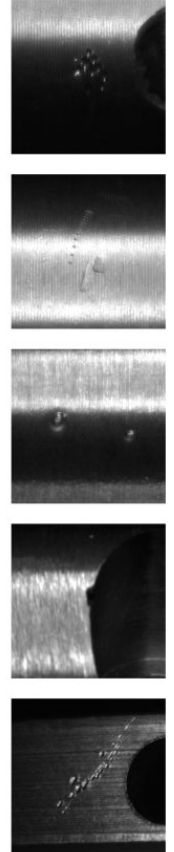
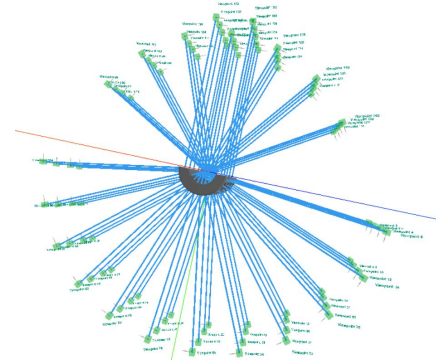
# Introduction

- Defects are diverse and rare → Data shortage



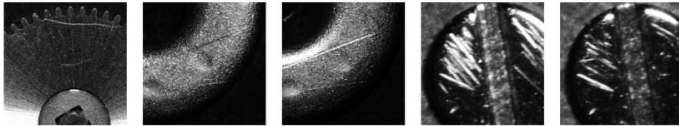
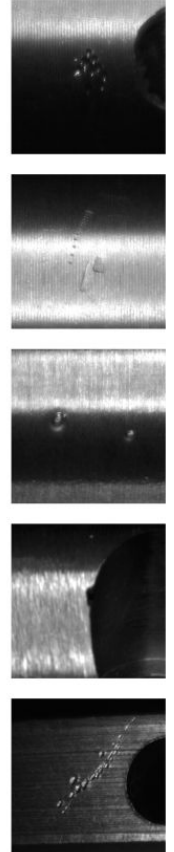
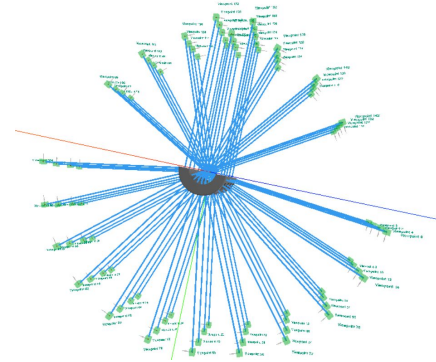
# Introduction

- Defects are diverse and rare → Data shortage
- Complex geometry → Complex inspection setups

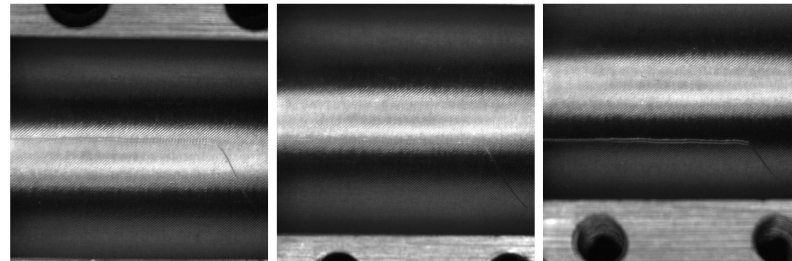


# Introduction

- Defects are diverse and rare → Data shortage
- Complex geometry → Complex inspection setups
- Textured metal surfaces are challenging

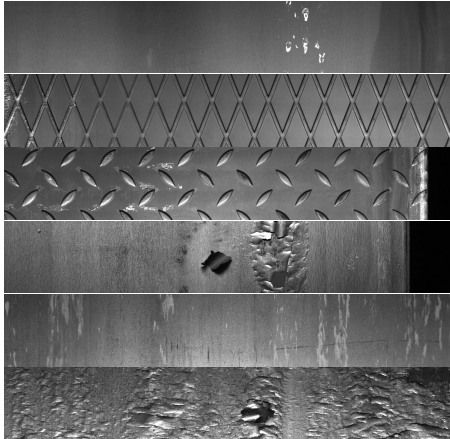


Honzátko, D. et.al.: Defect segmentation for multi-illumination quality control systems (2021)



# Existing research

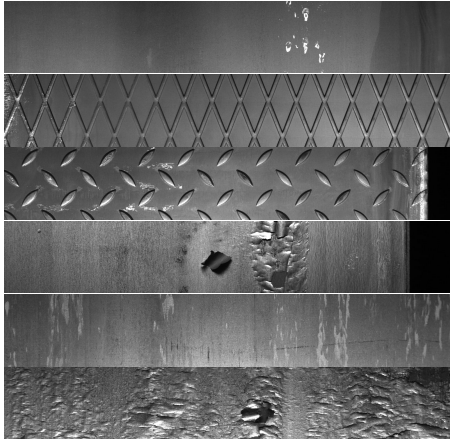
- Large datasets, but planar geometry



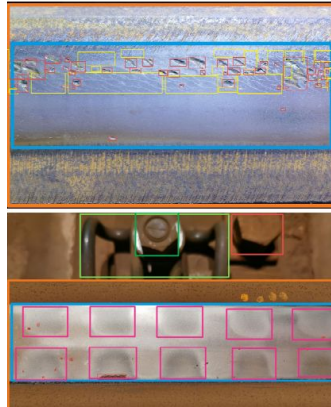
PAO Severstal: Severstal: Steel defect detection (2019)

# Existing research

- Large datasets, but planar geometry
- Curved geometry, but uncontrolled environment



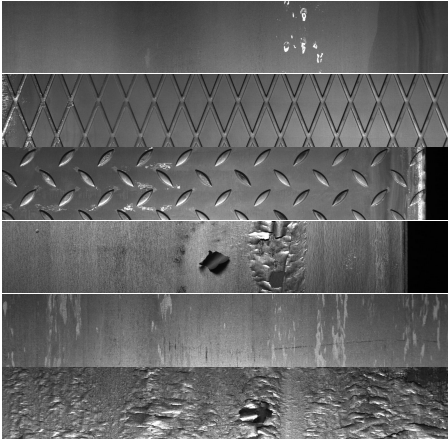
PAO Severstal: Severstal: Steel defect detection (2019)



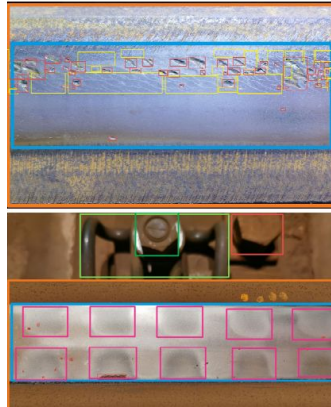
Zhang Z. et. al.: Rail-5k: a Real-World Dataset for Rail Surface Defects Detection (2021)

# Existing research

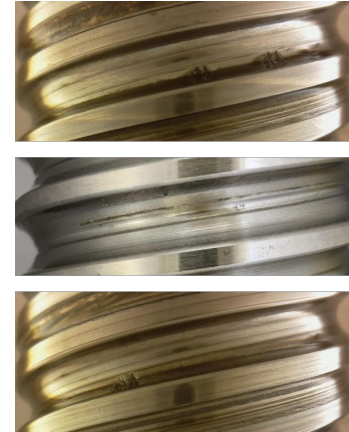
- Large datasets, but planar geometry
- Curved geometry, but uncontrolled environment
- Complex geometry, but flat surface texture



PAO Severstal: Severstal: Steel defect detection (2019)



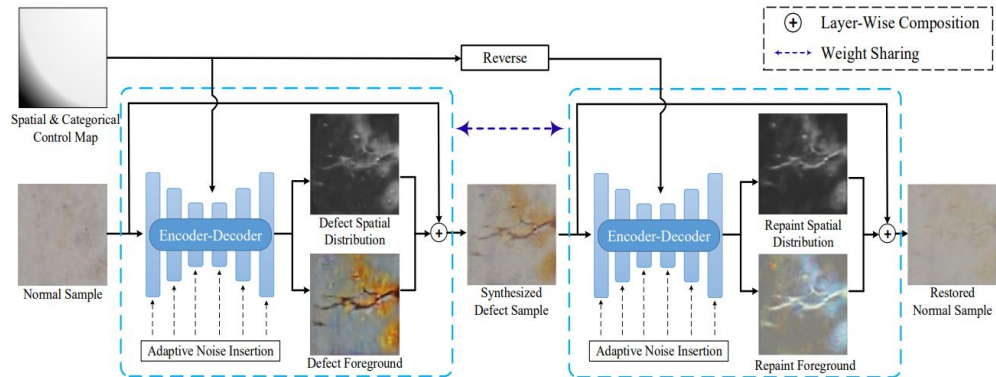
Zhang Z. et. al.: Rail-5k: a Real-World Dataset for Rail Surface Defects Detection (2021)



Schlagenhauf T. et. al.: Industrial Machine Tool Component Surface Defect Dataset (2021)

# Existing research

- Trained generative models for data generation is problematic:
  - Requires data with a lot of variety
  - Difficult to guarantee image quality
  - Difficult to extend support while preserving existing



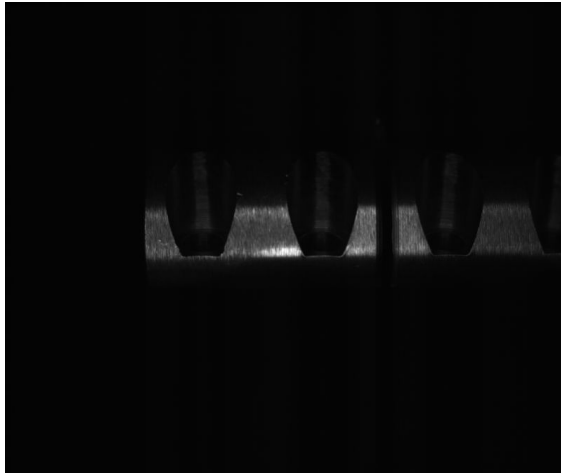
Zhang G. et. al.: Defect-GAN: High-Fidelity Defect Synthesis for Automated Defect Inspection (2021)



# Our contributions

- New dataset for defect recognition → complex surface geometry and texture

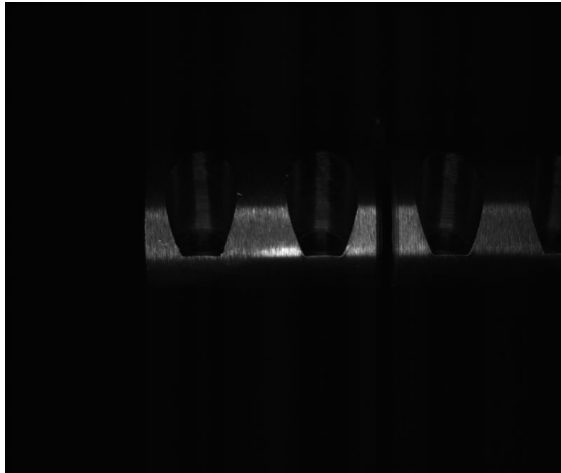
Real data →



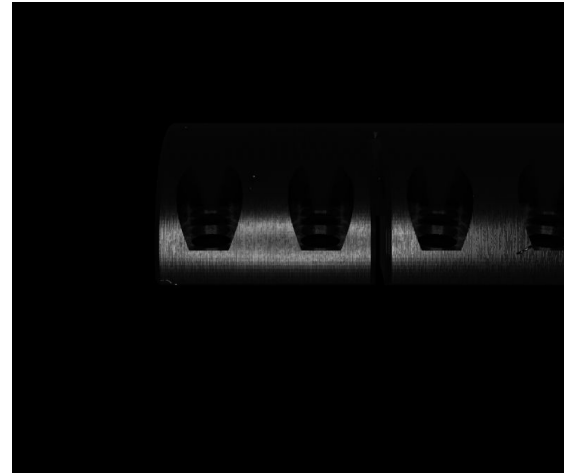
# Our contributions

- New dataset for defect recognition → complex surface geometry and texture
- Synthetic dataset equivalent → using recent procedural methods by Bosnar et.al.

Real data →



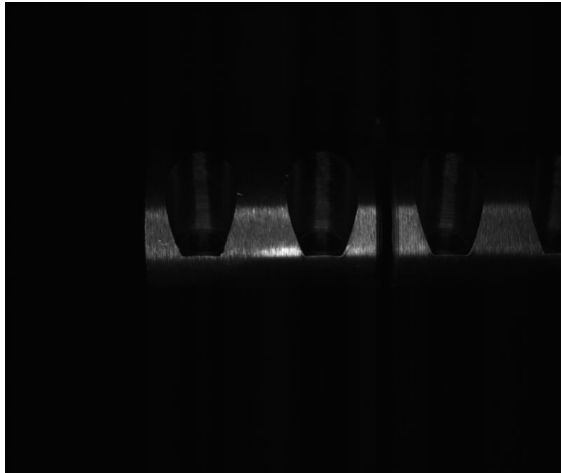
← Synth data



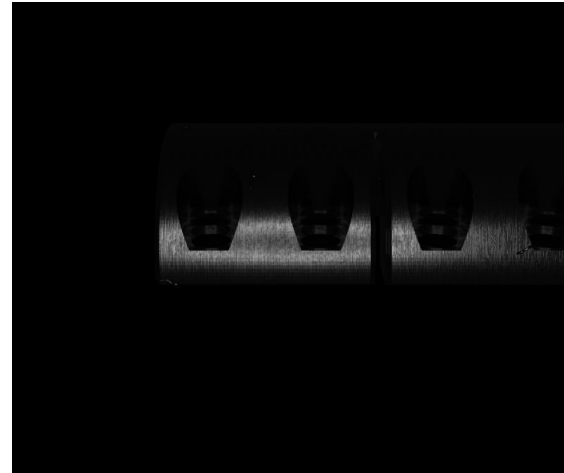
# Our contributions

- New dataset for defect recognition → complex surface geometry and texture
- Synthetic dataset equivalent → using recent procedural methods by Bosnar et.al.
- Comparative study: custom synthetic data or similar datasets

Real data →



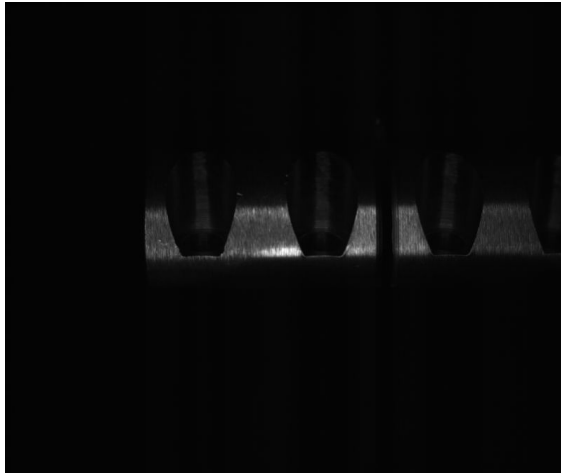
← Synth data



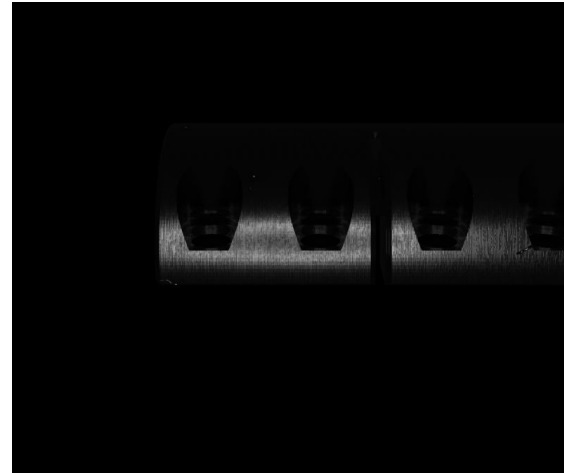
# Our contributions

- New dataset for defect recognition → complex surface geometry and texture
- Synthetic dataset equivalent → using recent procedural methods by Bosnar et.al.
- Comparative study: custom synthetic data or similar datasets
- Methods for improving model performance

Real data →



← Synth data



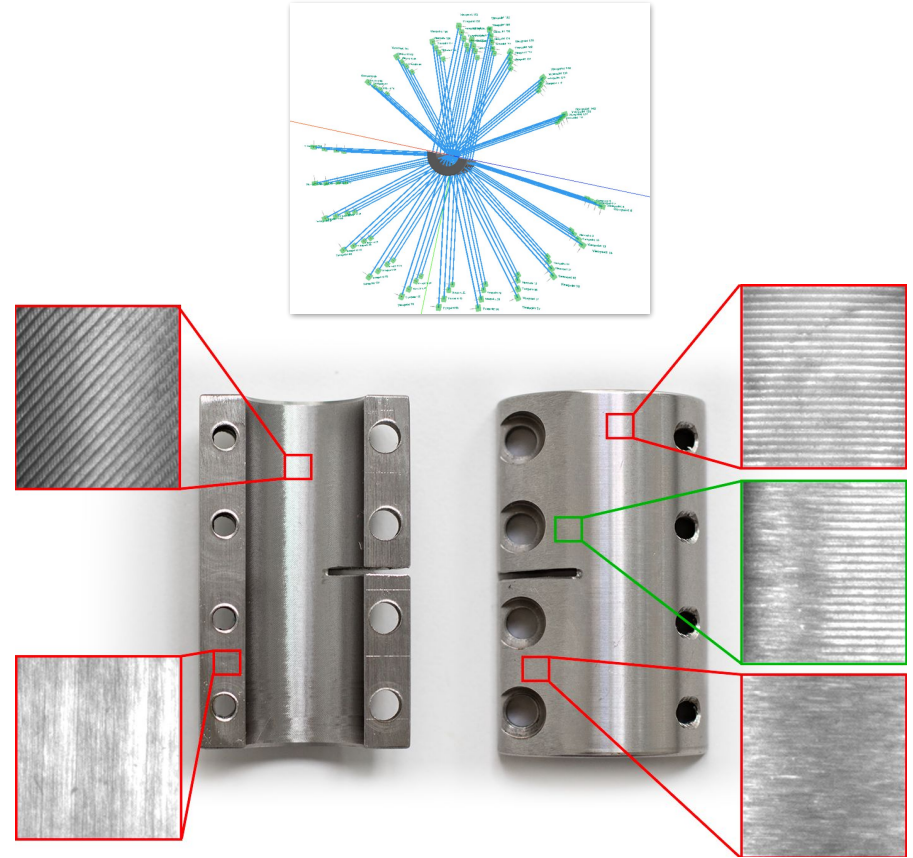
# RealClutch dataset

## Description

- 6 objects, 3 manually defected
- 4 distinct surface textures
- 2 variations of inner milling texture
- Acquisition in dark environment
- 516 images (grayscale)
- Manually annotated only significant defects

## Goal

- Image segmentation of significant defects



# Random cropping

Image sample 1

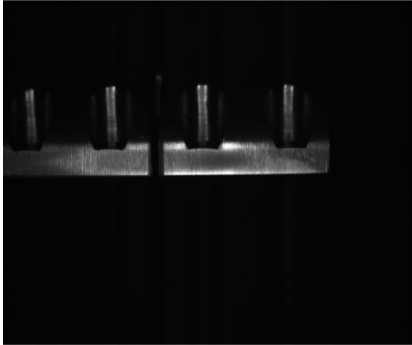
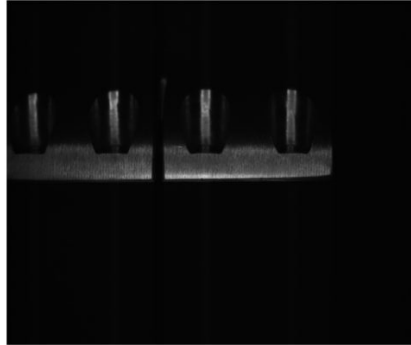
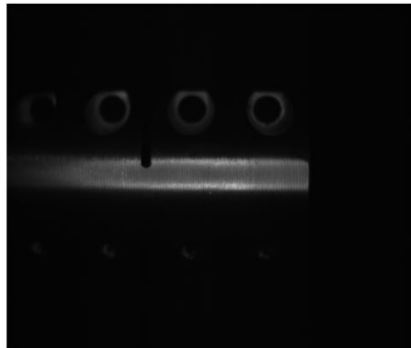
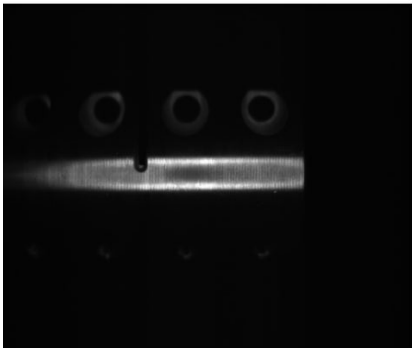


Image sample 2



- Large images (halved to 1224x1025)



# Random cropping

Image sample 1

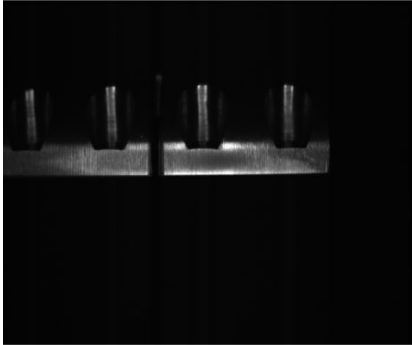
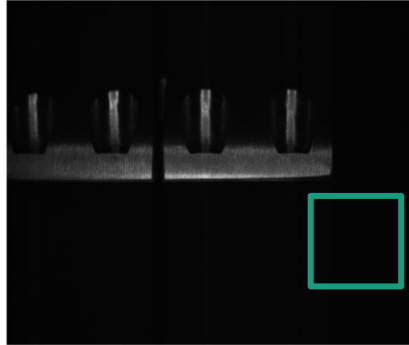
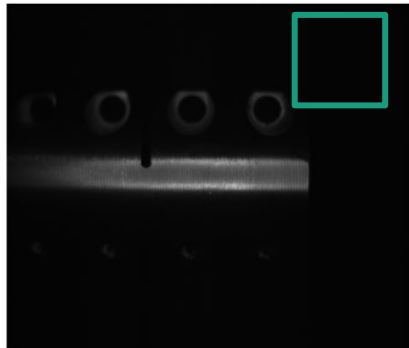
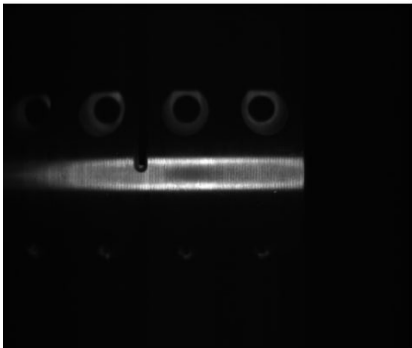


Image sample 2

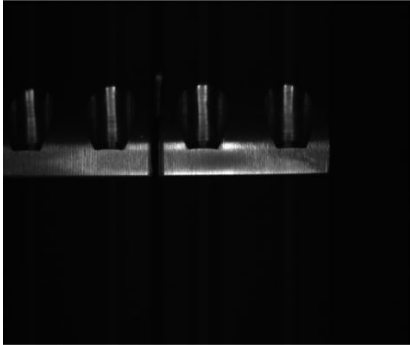


- Large images (halved to 1224x1025)
- Many random crops end up in dark regions (background)

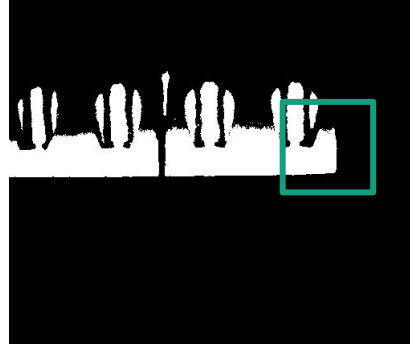


# Random cropping

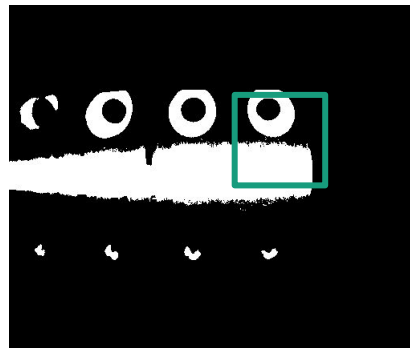
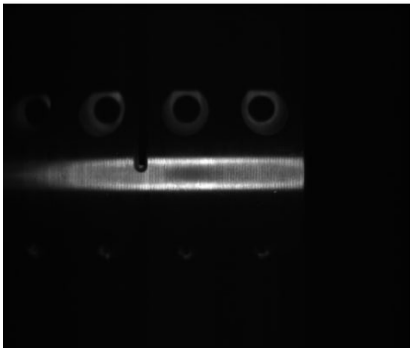
Image



Thresholded



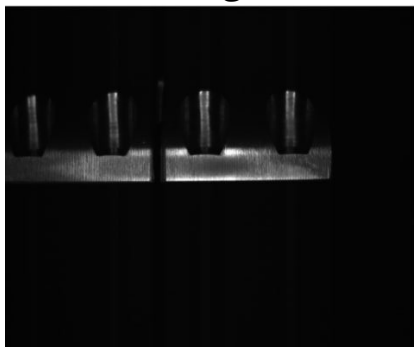
- Large images (halved to 1224x1025)
- Many random crops end up in dark regions (background)
- Bias cropping to higher intensities



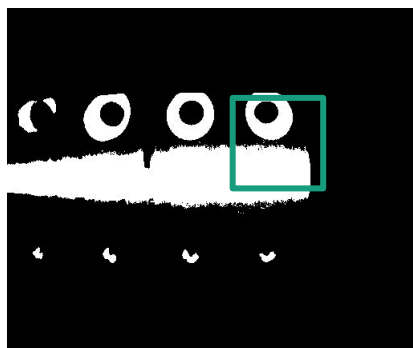
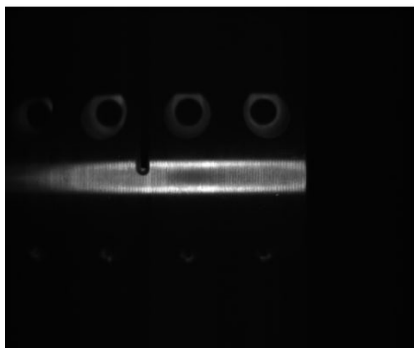
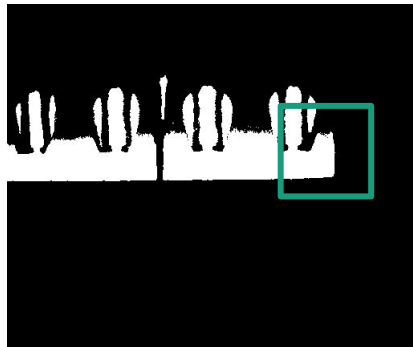


# Random cropping

Image

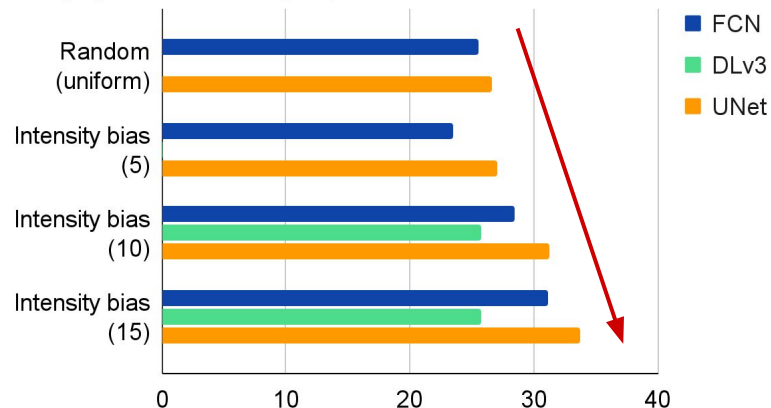


Thresholded



- Large images (halved to 1224x1025)
- Many random crops end up in dark regions (background)
- Bias cropping to higher intensities
- Higher performance and stability

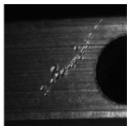
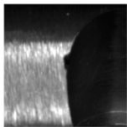
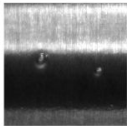
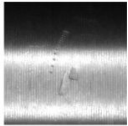
F1 [%] on RealClutch (test)



# Comparative study

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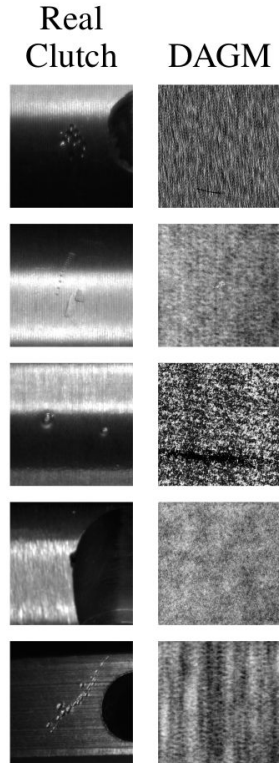
Real  
Clutch



## Similarities:

- Defect shapes and material
- Surface material
- Shadowing effect of curved surfaces
- Complex geometry and multiple textures
- Defect visibility changes
- Similar geometry and acquisition setup

# Comparative study - DAGM

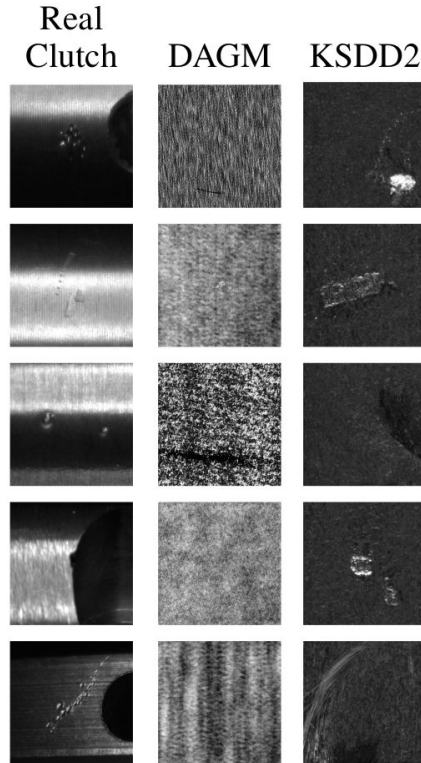


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Wieler M. et. al.: Weakly supervised learning for industrial optical inspection (2007)

# Comparative study - Kolektor Surface Defects Dataset v2

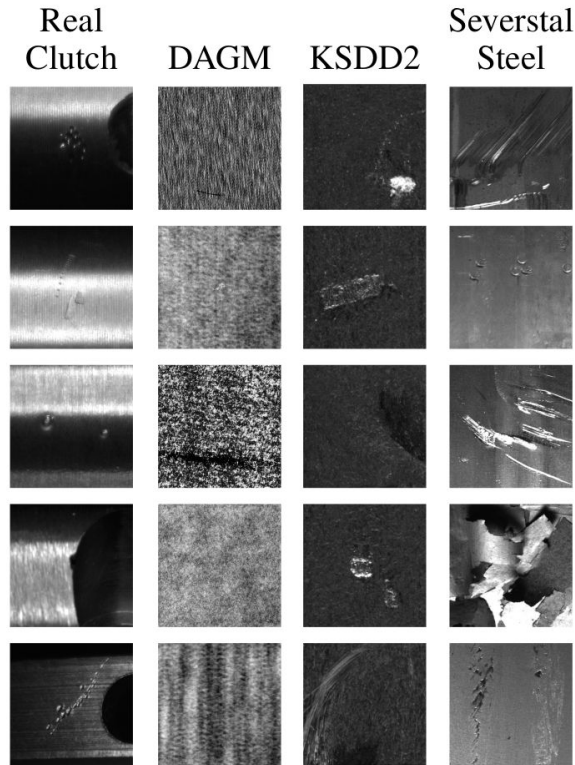


Similarities:

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Božič J. et. al.: Mixed supervision for surface-defect detection: from weakly to fully supervised learning (2021)

# Comparative study - Severstal Steel dataset

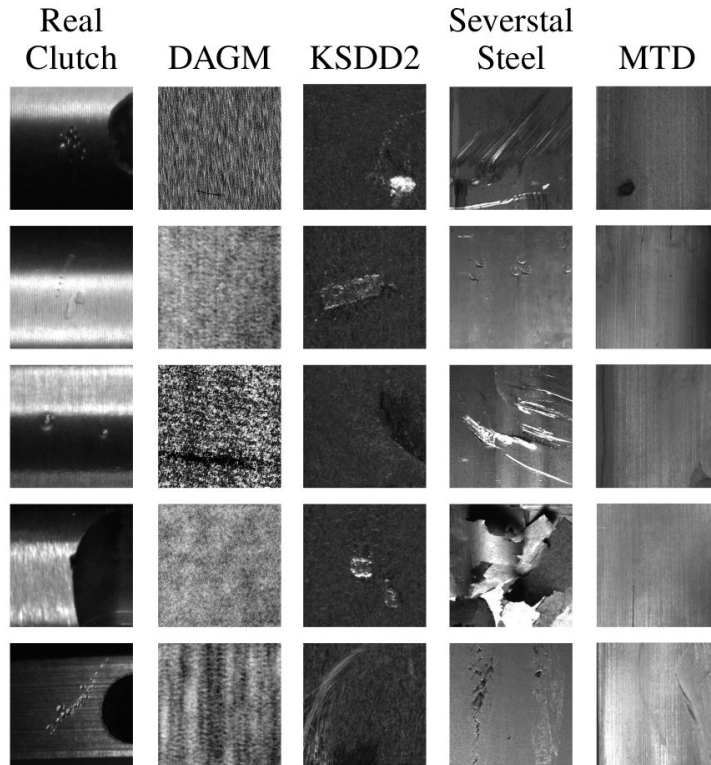


PAO Severstal: Severstal: Steel Defect Detection (2019)

Similarities:

- + Defect shapes and material
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# Comparative study - Magnetic Tile Defects dataset

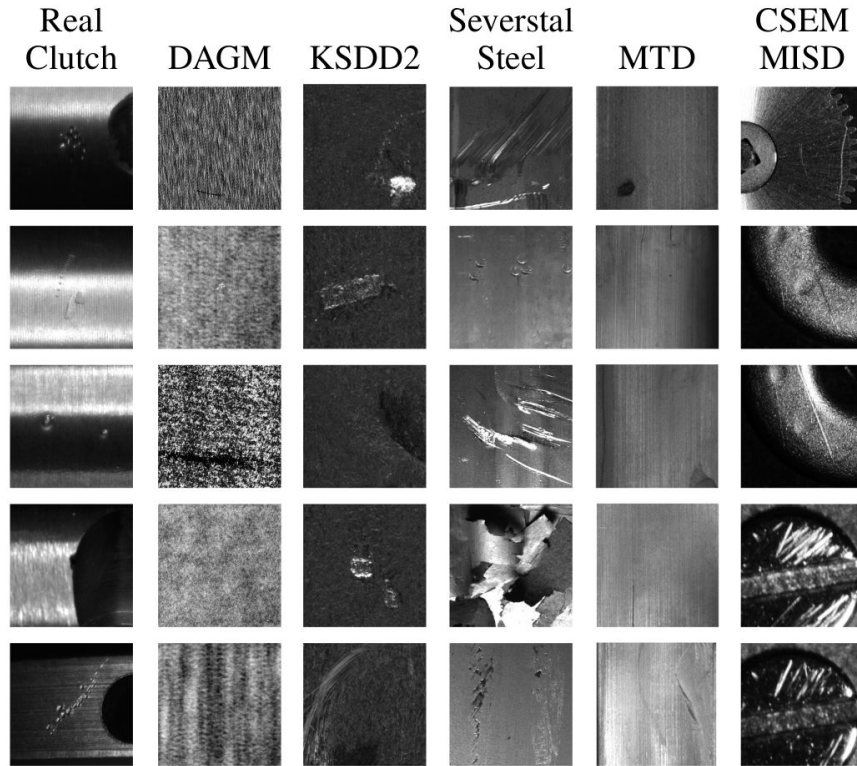


Similarities:

- + Defect shapes and material
- + Surface material
- + Shadowing effect of curved surfaces
- Complex geometry and multiple textures
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- Similar geometry and acquisition setup

Huang Y. et. al.: Surface defect saliency of magnetic tile (2018)

# Comparative study - CSEM Multi Illumination Surface Defect detection dataset



Similarities:

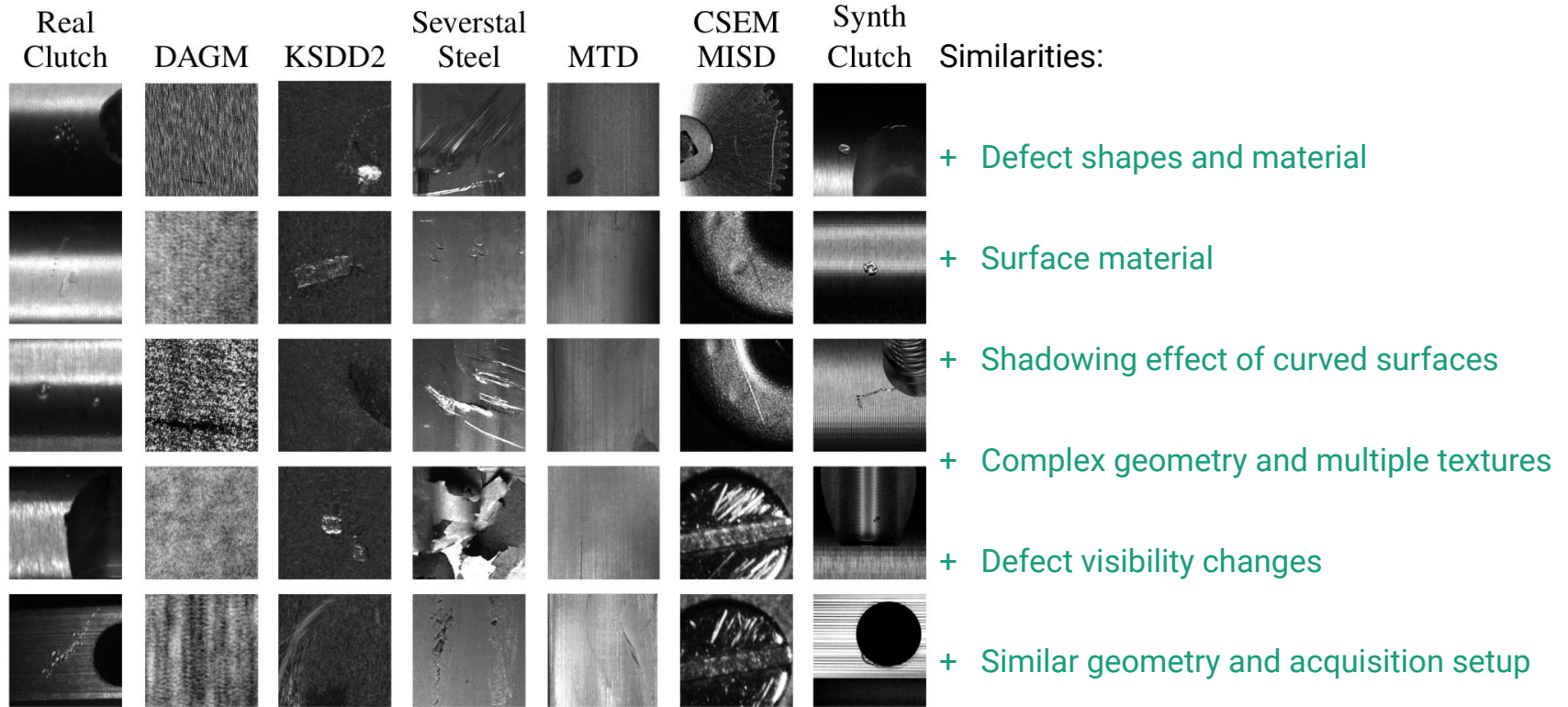
- + Defect shapes and material
- + Surface material
- + Shadowing effect of curved surfaces
- + Complex geometry and multiple textures
- + Defect visibility changes

- Similar geometry and acquisition setup

Honzátko, D. et.al.: Defect segmentation for multi-illumination quality control systems (2021)



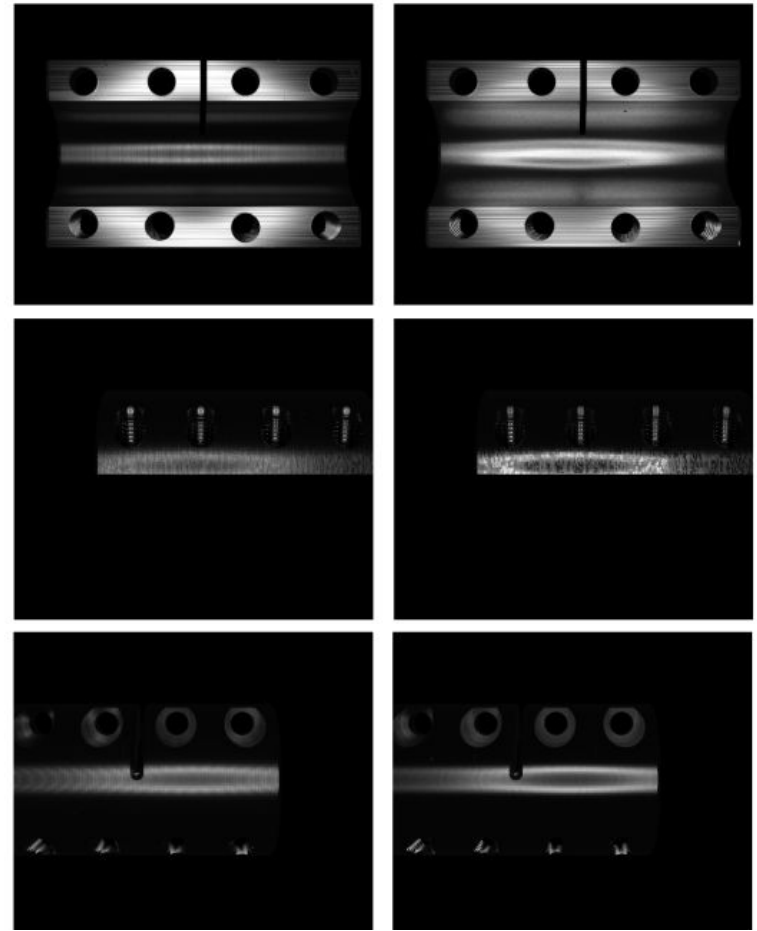
# Comparative study - SynthClutch



# SynthClutch dataset

## Description

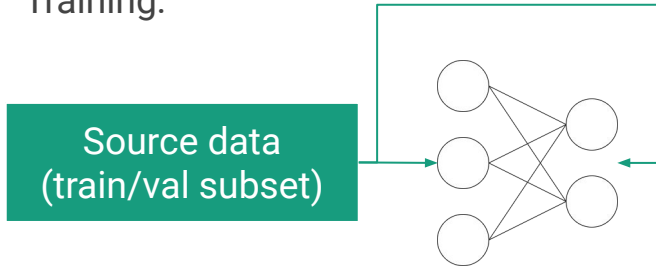
- 40 objects, procedurally defected and textured CAD model
- Defect, material and texture parameters sampled within specified ranges
- 3440 rendered images (grayscale)
- Rendered with segmentation annotations



- L. Bosnar et.al.: Image synthesis pipeline for surface inspection (2020)  
L. Bosnar et.al.: Texture synthesis for surface inspection (2022)  
L. Bosnar et.al.: Procedural defect modeling for virtual surface inspection environments (2023)

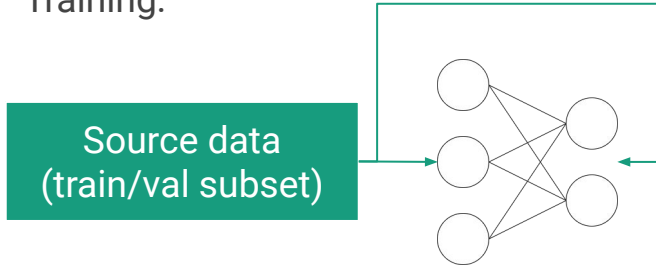
# Results

Training:

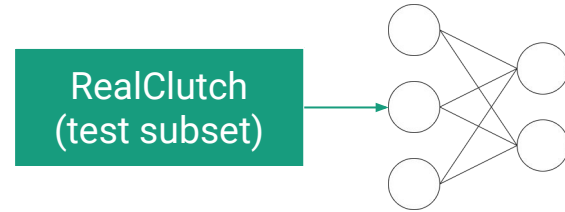


# Results

Training:

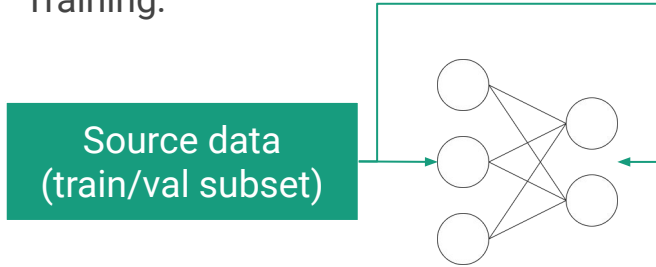


Testing:

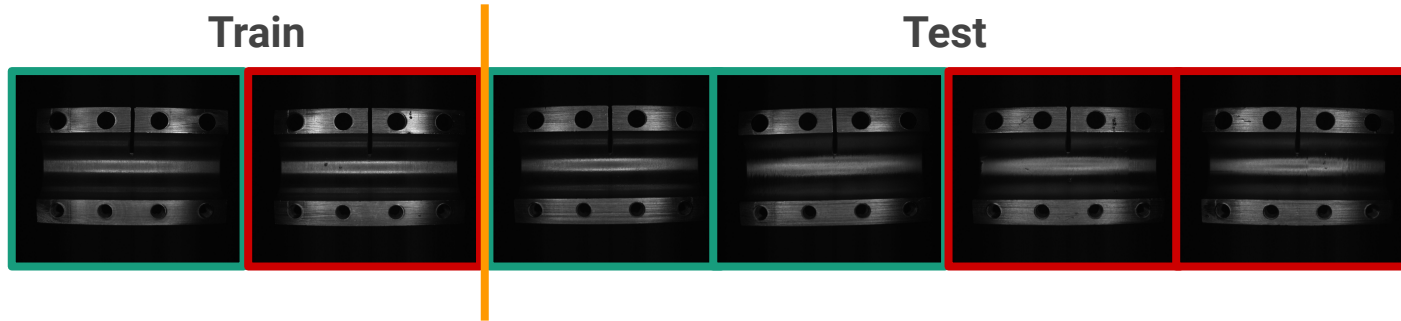
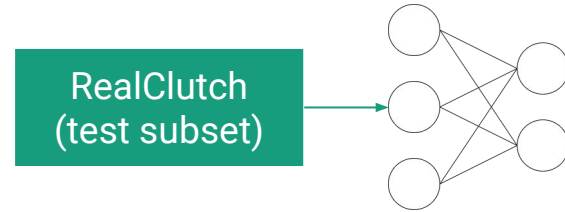


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Training:

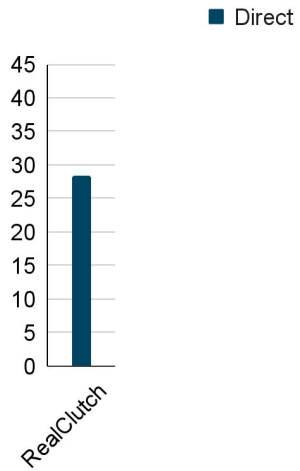


Testing:

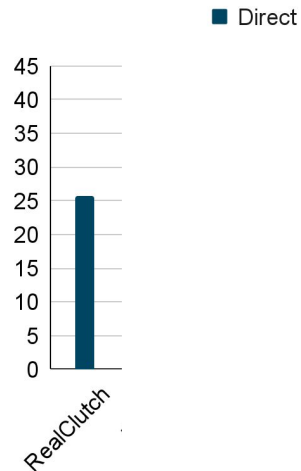


# Results - Baseline

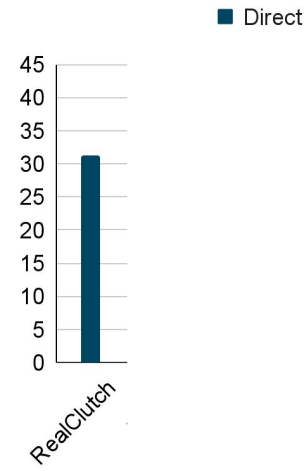
F1 [%] - Fully-convolutional network



F1 [%] - DeepLabv3

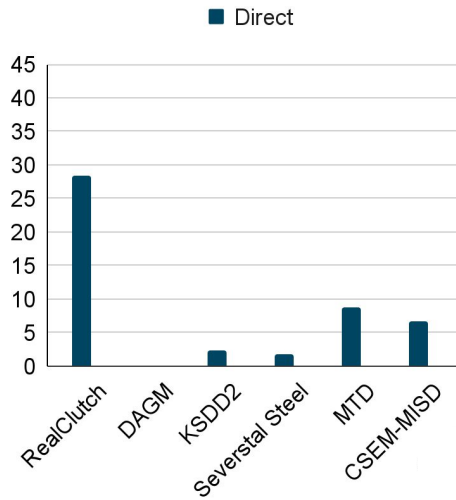


F1 [%] - U-Net

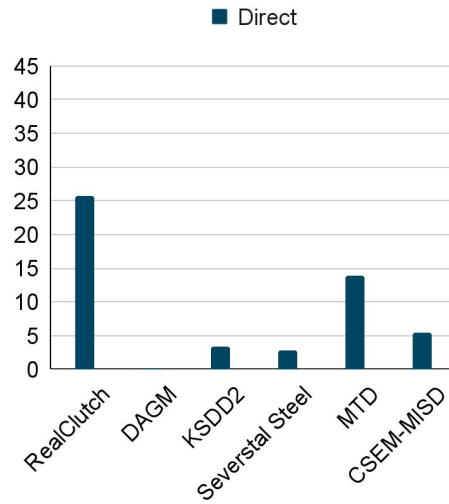


# Results - Related datasets

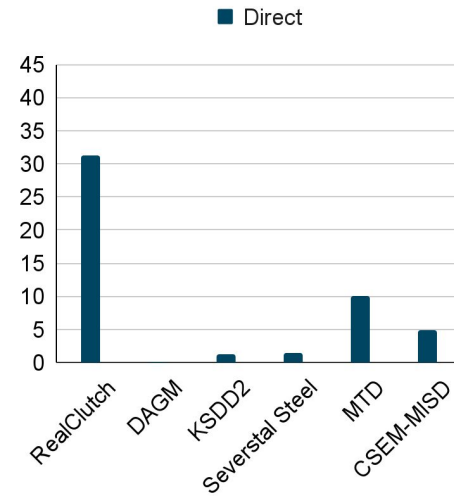
F1 [%] - Fully-convolutional network



F1 [%] - DeepLabv3

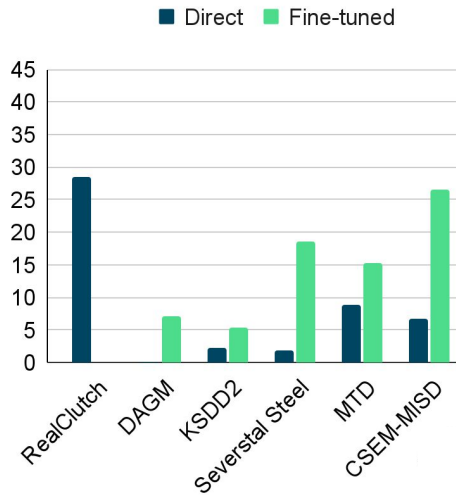


F1 [%] - U-Net

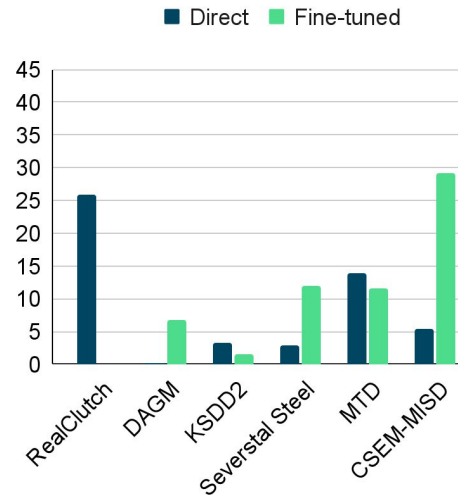


# Results - Related datasets + Fine-tuning

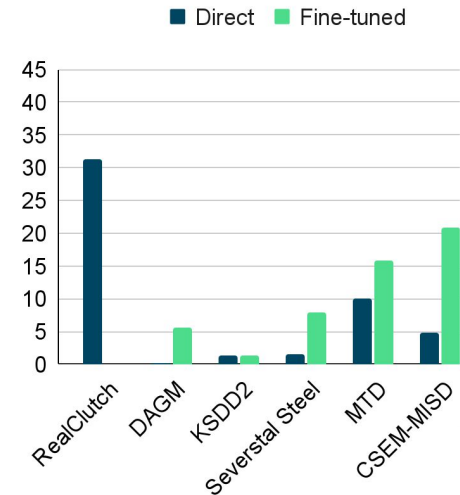
F1 [%] - Fully-convolutional network



F1 [%] - DeepLabv3



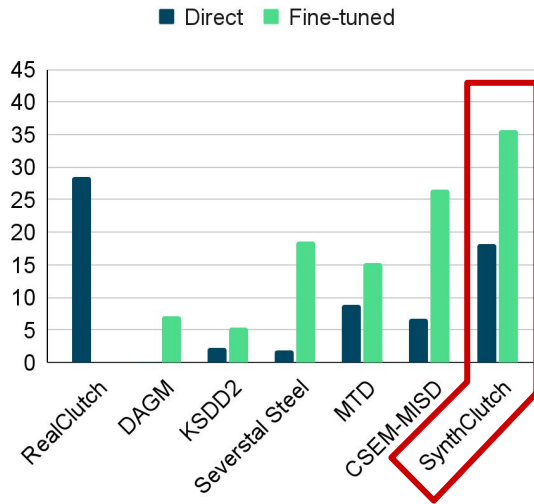
F1 [%] - U-Net



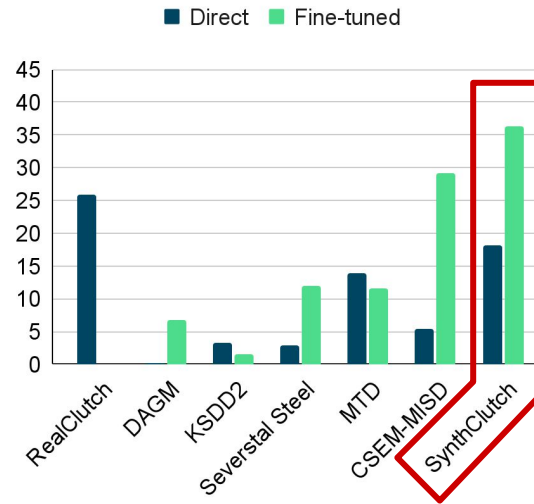


# Results - SynthClutch

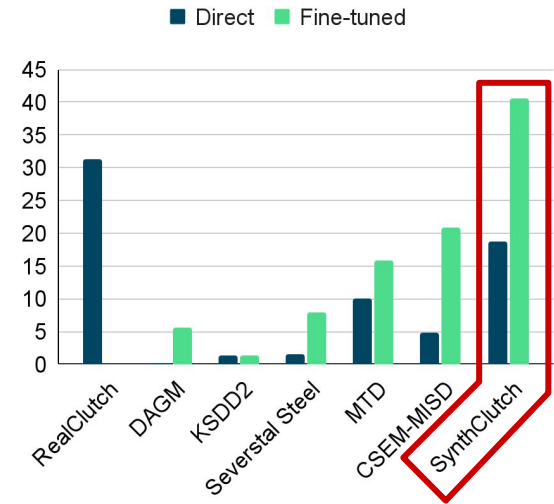
F1 [%] - Fully-convolutional network



F1 [%] - DeepLabv3

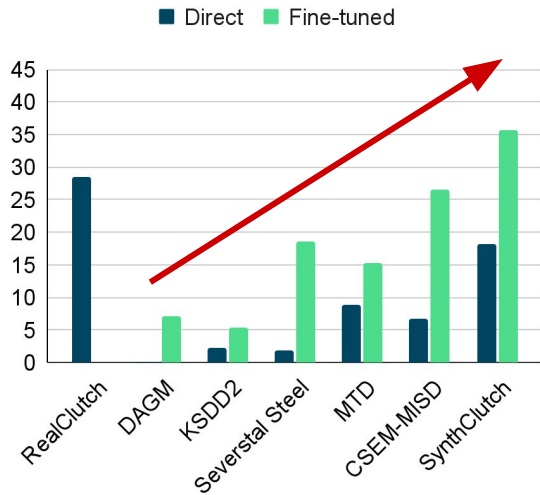


F1 [%] - U-Net

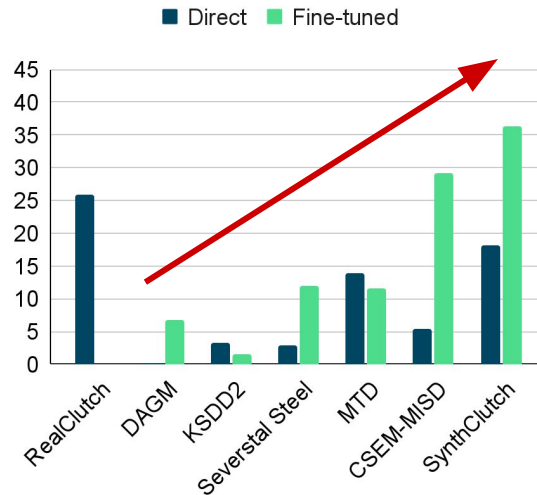


# Results - Performance trend

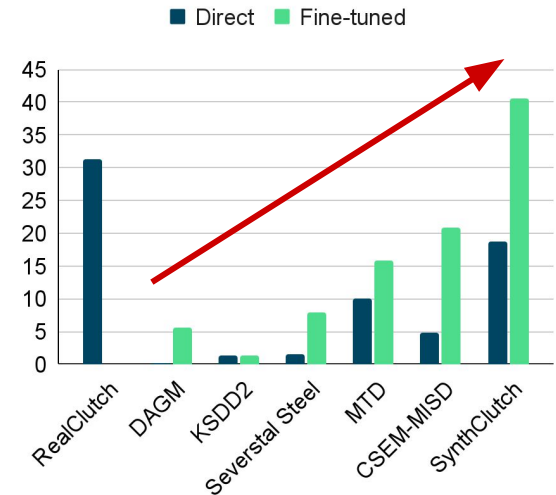
F1 [%] - Fully-convolutional network



F1 [%] - DeepLabv3

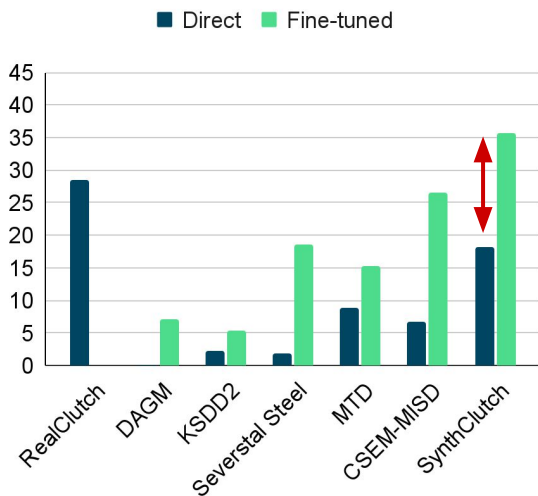


F1 [%] - U-Net

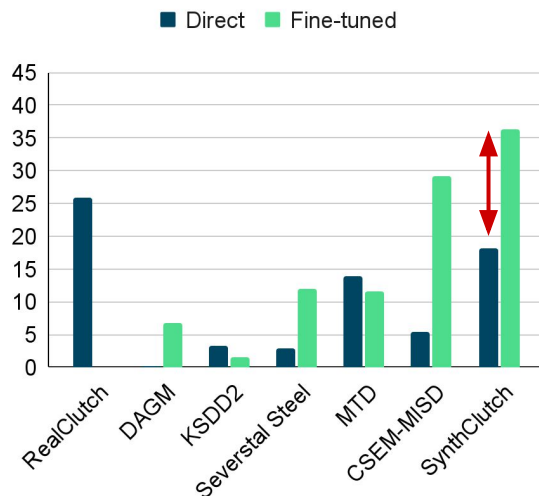


# Results - Domain gap

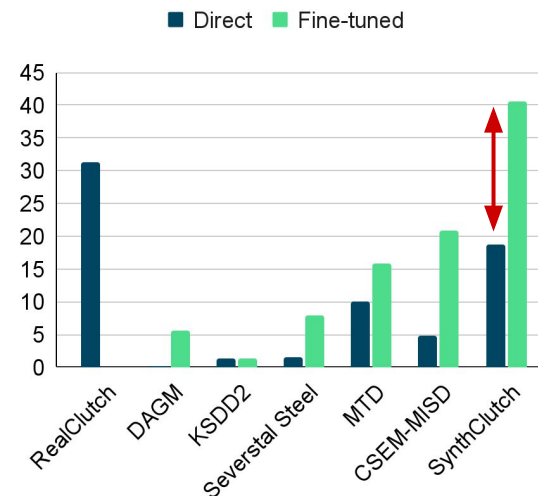
F1 [%] - Fully-convolutional network



F1 [%] - DeepLabv3



F1 [%] - U-Net

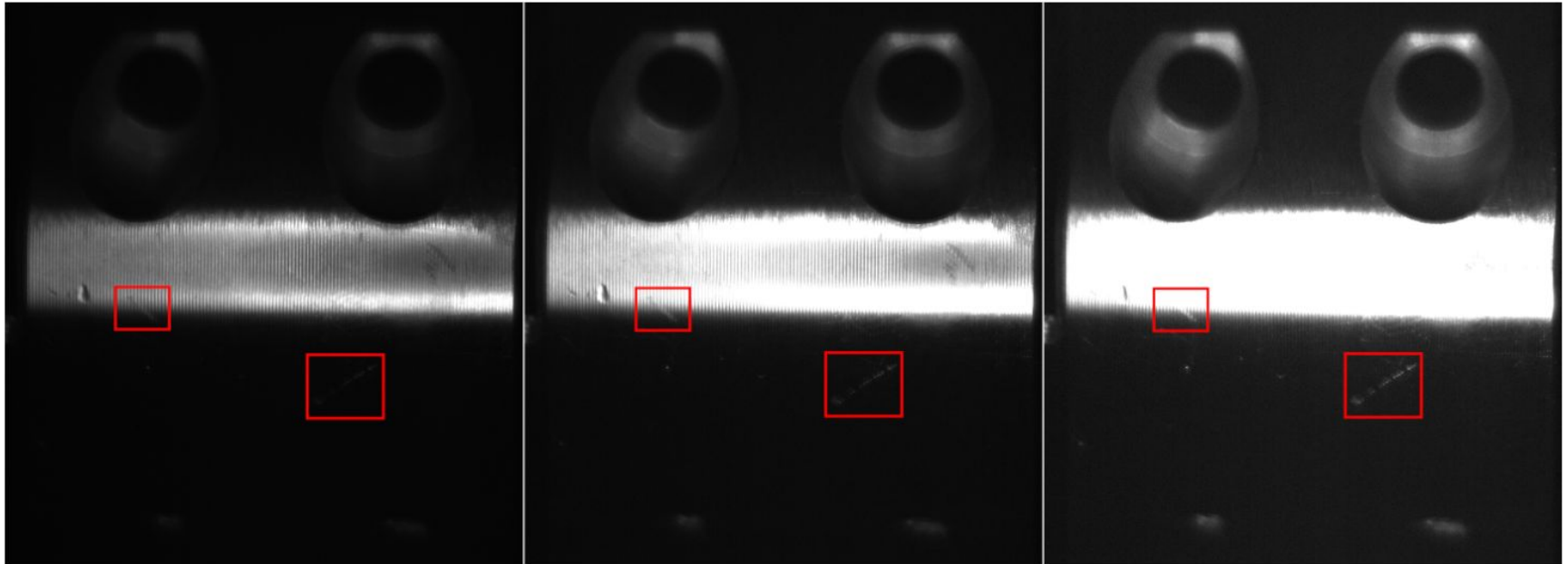


# Exposure stacking - Defect appearance change

Original

Exposure 1

Exposure 2

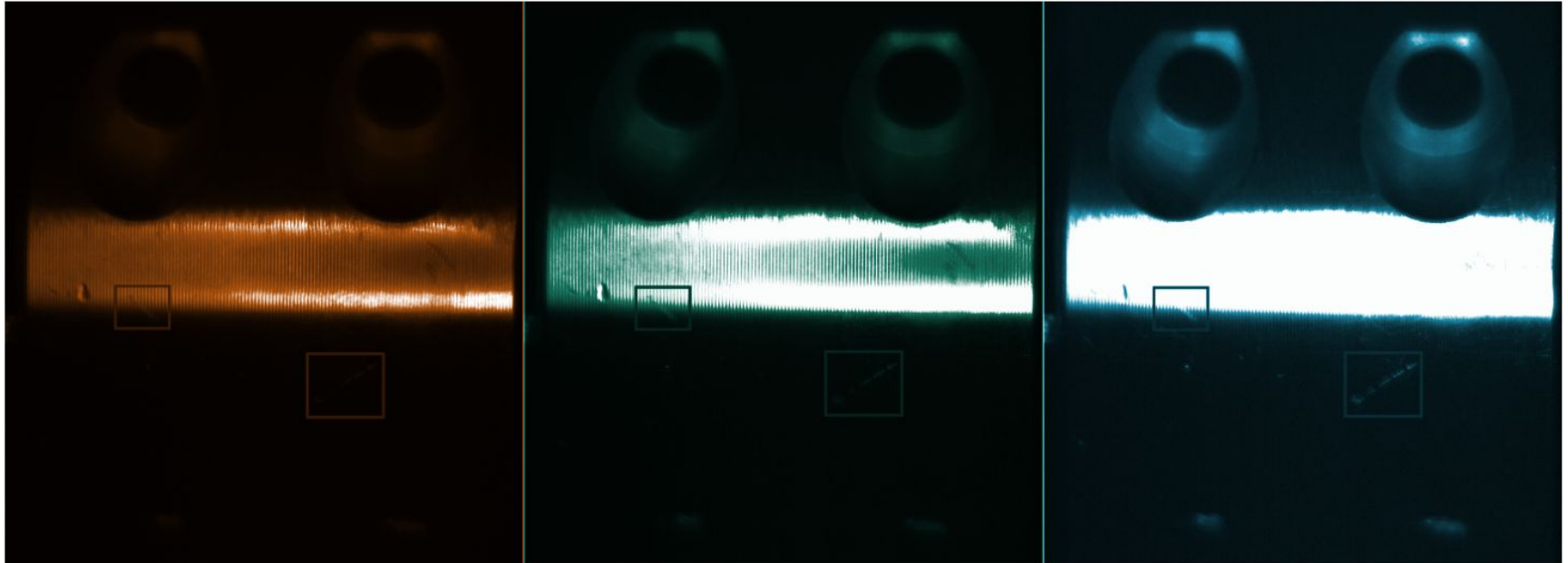


# Exposure stacking - Defect appearance change

Original

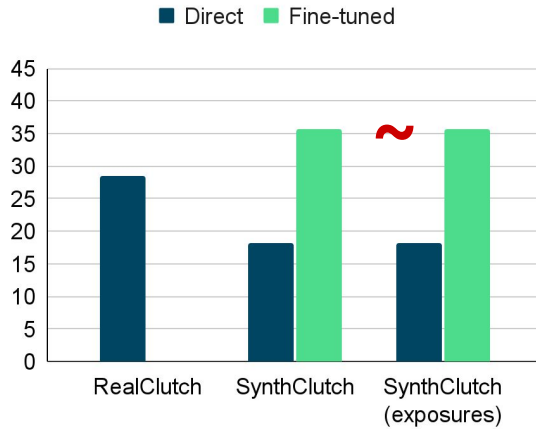
Exposure 1

Exposure 2

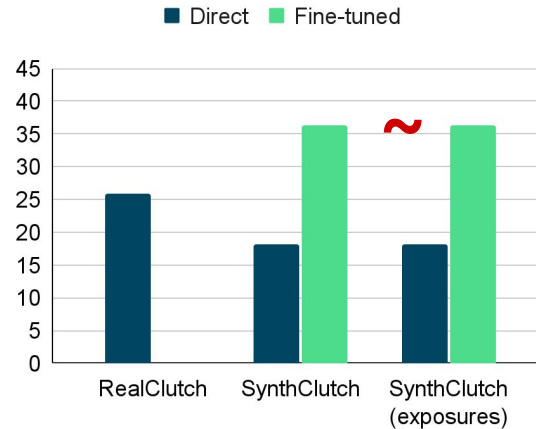


# Exposure stacking - Results

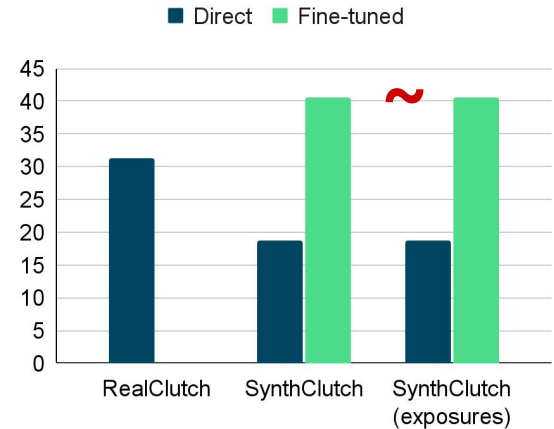
F1 [%] - Fully-convolutional network



F1 [%] - DeepLabv3



F1 [%] - U-Net



# Conclusions

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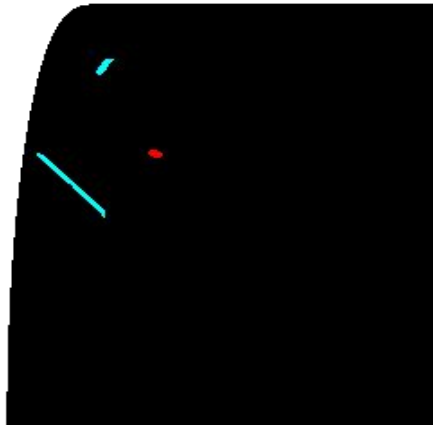
- Introduced a new dual dataset for surface inspection
- Custom synthetic dataset is superior to similar datasets
- Small amount of real data is still needed
- Intensity biased cropping benefits the learning process

# Conclusions

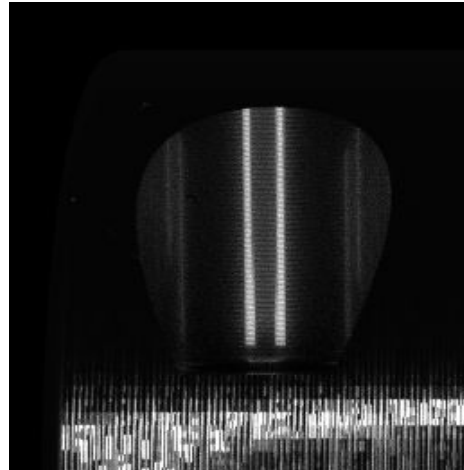
- Introduced a new dual dataset for surface inspection
- Custom synthetic dataset is superior to similar datasets
- Small amount of real data is still needed
- Intensity biased cropping benefits the learning process
- Stack of modified exposures does not increase model performance

# Limitations and further research

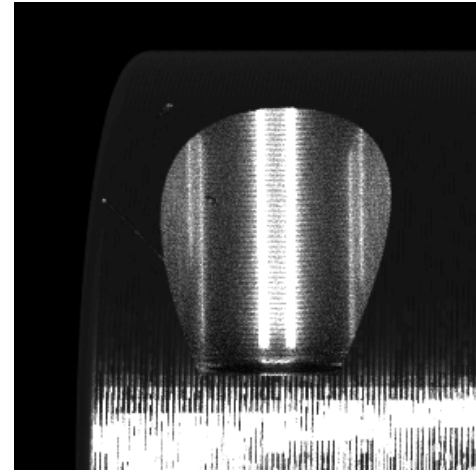
- Synthetic masks are over-labeling



Mask



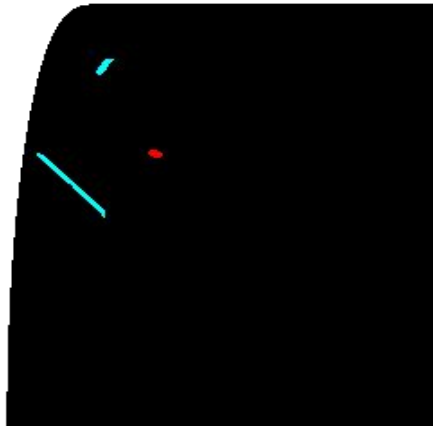
Image



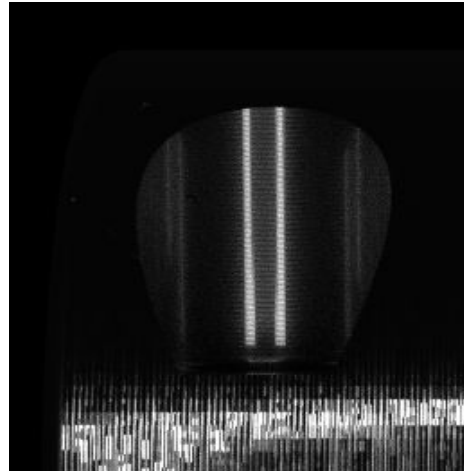
Overexposed image

# Limitations and further research

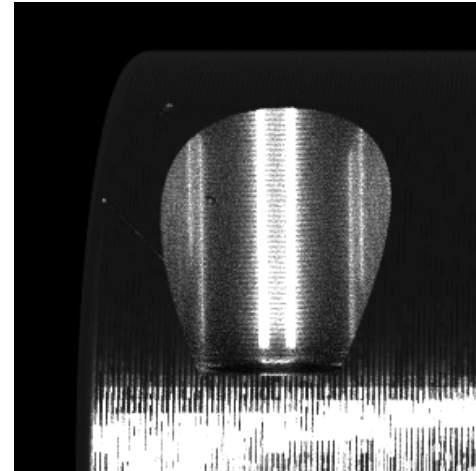
- Synthetic masks are over-labeling
  - Problem of defect visibility



Mask



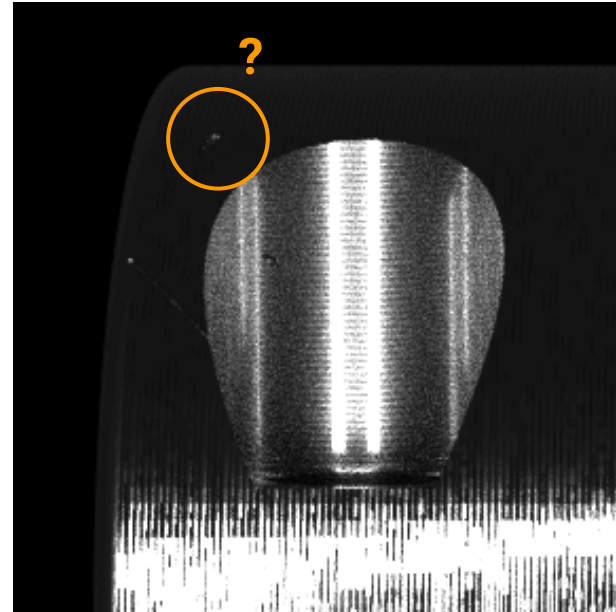
Image



Overexposed image

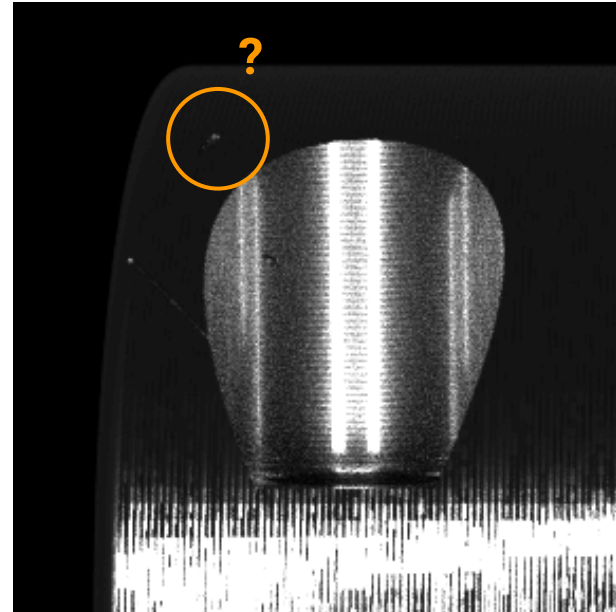
# Limitations and further research

- Synthetic masks are over-labeling
  - Problem of defect visibility
- Decision making based on single image



# Limitations and further research

- Synthetic masks are over-labeling
  - Problem of defect visibility
- Decision making based on single image
- Exploring the possibilities of procedural synthetic data in different industrial inspection setups



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# Thank you for listening!

This work was supported by Fraunhofer ITWM and the German Federal Ministry of Education and Research (BMBF) [grant number 01IS21058B (SynosIs)].

We thank Maedler for providing us with the correct object samples and consent to use them for research.

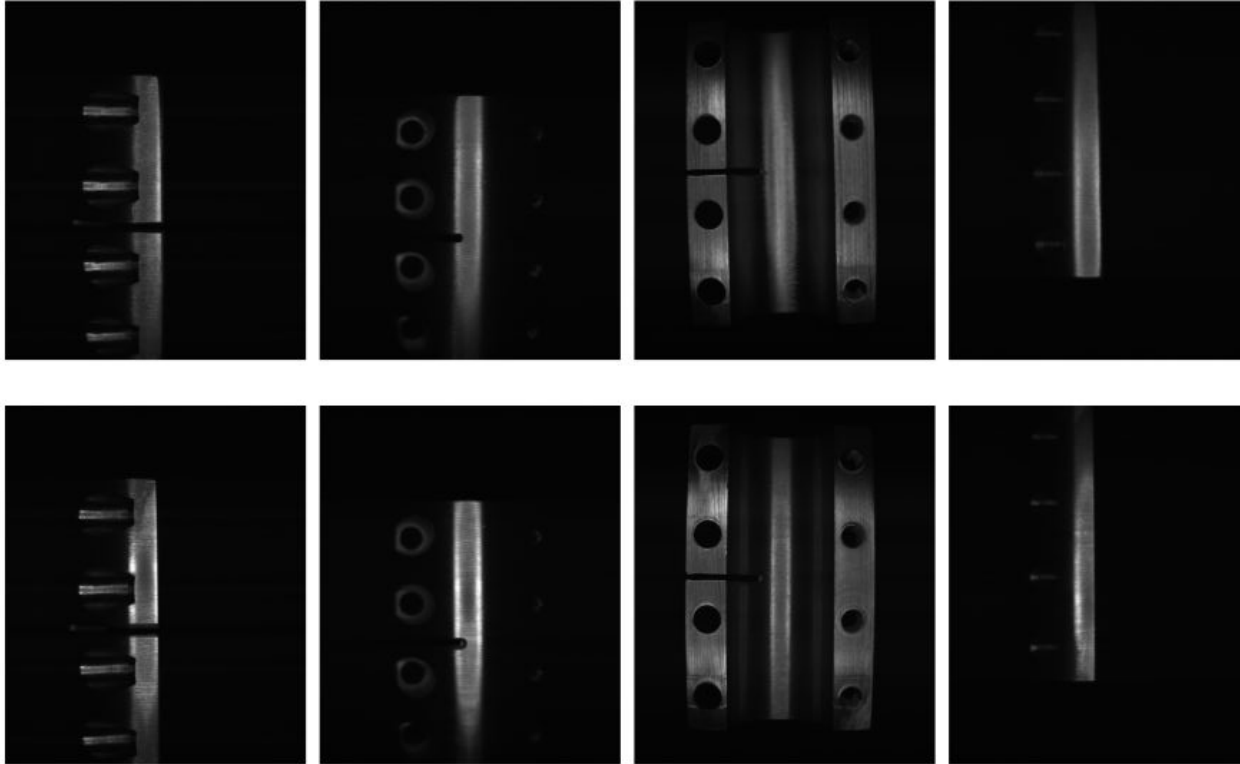


Rheinland-Pfälzische  
Technische Universität  
Kaiserslautern  
Landau

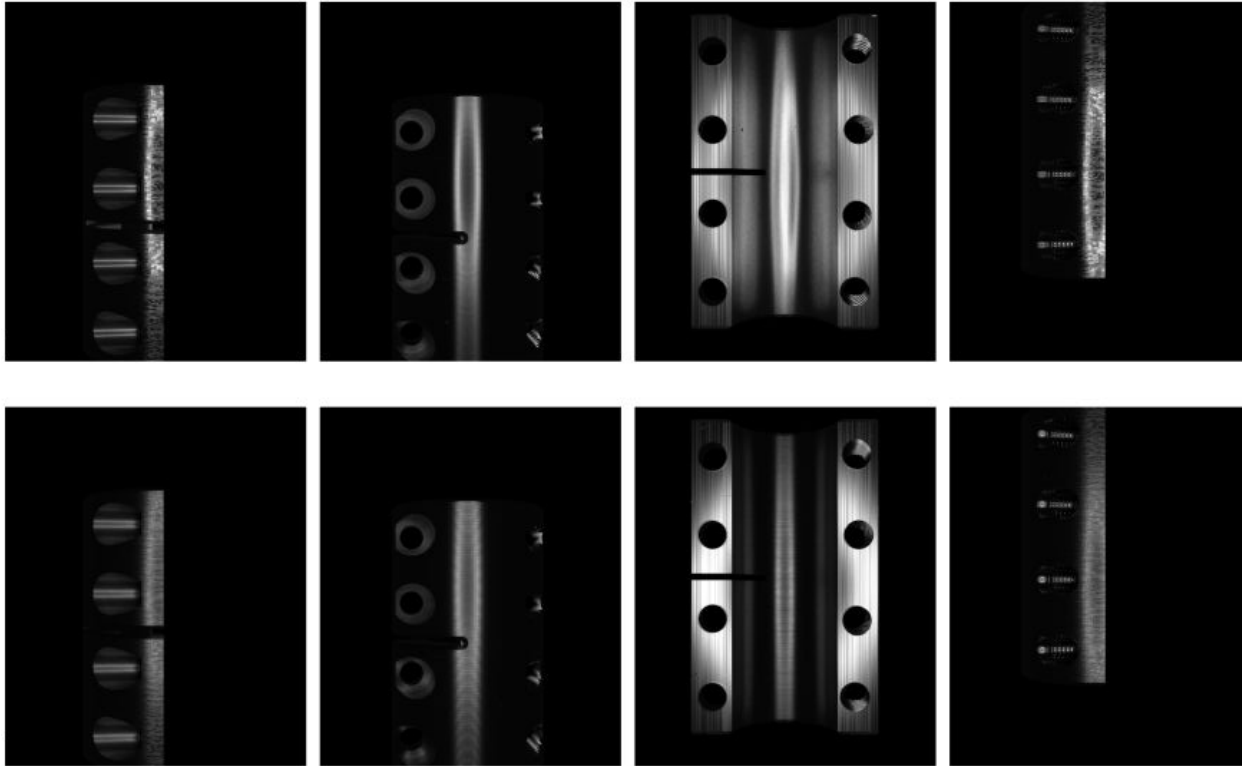


# Extra slides

# RealClutch dataset



# SynthClutch dataset



# Introduction



Defect recognition approaches	Expensive annotation	Requires lot of defect data	Requires lot of correct data
Supervised (detection, segmentation)	+	+	+
Weakly-supervised (class activation maps)	-	+	+
Anomaly detection	-	-	+